

Notice of References Cited	Application/Control No. 10/642,760		Applicant(s)/Patent Under Reexamination TSUCHIYA ET AL.	
	Examiner Sheela C. Chawan		Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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	U	Haruo Yoda et al., " repeating pattern defect detection device", 11/01/1984 United States Patent and Trademark Office, Washington, D.C. March 2007. Pages 1-21.				
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.